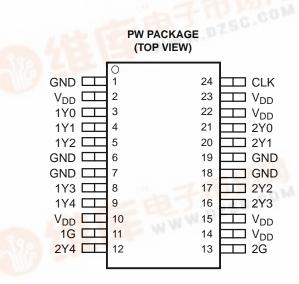


# 2.5-V TO 3.3-V HIGH-PERFORMANCE CLOCK BUFFER

- High-Performance 1:10 Clock Driver for General-Purpose Applications. Operates up to 200 MHz at V<sub>DD</sub> 3.3 V
- Pin-to-Pin Skew < 100 ps at V<sub>DD</sub> 3.3 V
- V<sub>DD</sub> Range: 2.3 V to 3.6 V
- Operating Temperature Range –40°C to 85°C
- Output Enable Glitch Suppression
- Distributes One Clock Input to Two Banks of Five Outputs
- 25-Ω On-Chip Series Damping Resistors
- Packaged in 24-Pin TSSOP



### DESCRIPTION

The CDCVF2310 is a high-performance, low-skew clock buffer that operates up to 200 MHz. Two banks of five outputs each provide low-skew copies of CLK. After power up, the default state of the outputs is low regardless of the state of the control pins. For normal operation, the outputs of bank 1Y[0:4] or 2Y[0:4] can be placed in a low state when the control pins (1G or 2G, respectively) are held low and a negative clock edge is detected on the CLK input. The outputs of bank 1Y[0:4] or 2Y[0:4] can be switched into the buffer mode when the control pins (1G and 2G) are held high and a negative clock edge is detected on the CLK input. The device operates in a 2.5-V and 3.3-V environment. The built-in output enable glitch suppression ensures a synchronized output enable sequence to distribute full period clock signals.

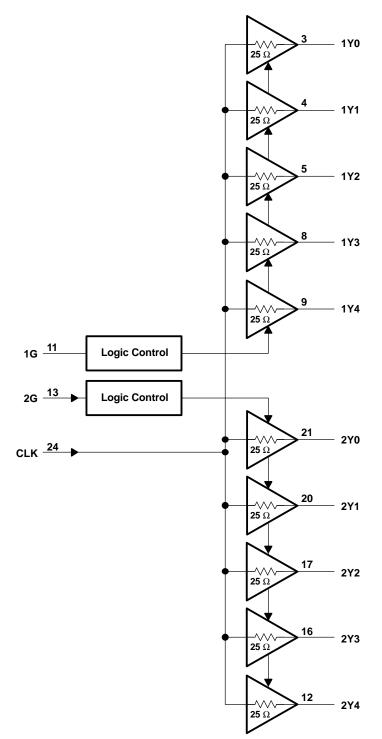
The CDCVF2310 is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas



#### FUNCTIONAL BLOCK DIAGRAM





## FUNCTION TABLE

INPUT			OUTPUT		
1G	2G	CLK	1Y[0:4]	2Y[0:4]	
L	L	$\downarrow$	L	L	
Н	L	$\downarrow$	CLK <sup>(1)</sup>	L	
L	н	$\downarrow$	L	CLK <sup>(1)</sup>	
Н	Н	$\downarrow$	CLK <sup>(1)</sup>	CLK <sup>(1)</sup>	

(1) After detecting one negative edge on the CLK input, the output follows the input CLK if the control pin is held high.

#### **Terminal Functions**

TERMINAL		I/O	DESCRIPTION	
NAME	NO.	1/0	DESCRIPTION	
1G	11	Ι	Output enable control for 1Y[0:4] outputs. This output enable is active-high, meaning the 1Y[0:4] clock outputs follow the input clock (CLK) if this pin is logic high.	
2G	13	I	Output enable control for 2Y[0:4] outputs. This output enable is active-high, meaning the 2Y[0:4] clock outputs follow the input clock (CLK) if this pin is logic high.	
1Y[0:4]	3, 4, 5, 8, 9	0	Buffered output clocks	
2Y[0:4]	21, 20, 17, 16, 12	0	Buffered output clocks	
CLK	24	I	Input reference frequency	
GND	1, 6, 7, 18, 19		Ground	
V <sub>DD</sub>	2, 10, 14, 15, 22, 23		DC power supply, 2.3 V – 3.6 V	



## DETAILED DESCRIPTION

#### **Output Enable Glitch Suppression Circuit**

The purpose of the glitch suppression circuitry is to ensure the output enable sequence is synchronized with the clock input such that the output buffer is enabled or disabled on the next full period of the input clock (negative edge triggered by the input clock) (see Figure 1).

The G input must fulfill the timing requirements  $(t_{su}, t_h)$  according to the *Switching Characteristics* table for predictable operation.

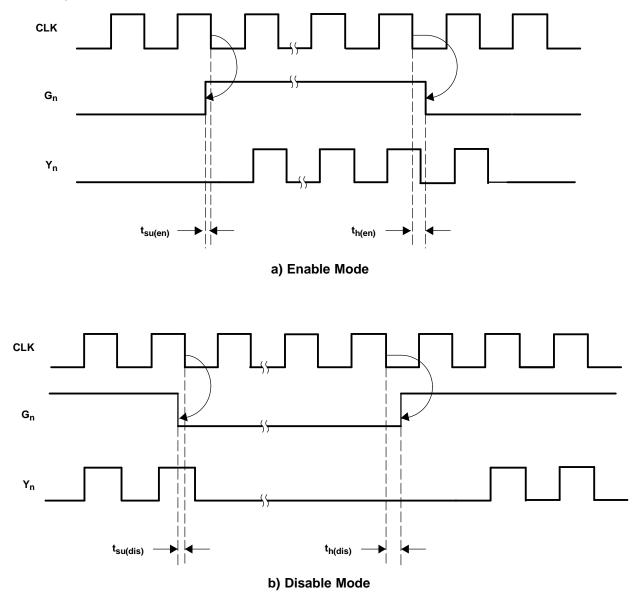


Figure 1. Enable and Disable Mode Relative to CLK $\downarrow$ 



## **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted) <sup>(1)</sup>

Supply voltage range, V <sub>DD</sub>	–0.5 V to 4.6 V
Input voltage range, V <sub>1</sub> <sup>(2)(3)</sup>	–0.5 V to V <sub>DD</sub> + 0.5 V
Output voltage range, $V_0^{(2)(3)}$	–0.5 V to V <sub>DD</sub> + 0.5 V
Input clamp current, $I_{IK}$ (V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>DD</sub> )	±50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{DD}$ )	±50 mA
Continuous total output current, $I_O (V_O = 0 \text{ to } V_{DD})$	±50 mA
Package thermal impedance, $\theta_{JA}^{(4)}$ : PW package	120°C/W
Storage temperature range T <sub>stg</sub>	−65°C to 150°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

(3) This value is limited to 4.6 V maximum.

(4) The package thermal impedance is calculated in accordance with JESD 51.

## **RECOMMENDED OPERATING CONDITIONS** <sup>(1)</sup>

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>DD</sub>		2.3	2.5		V
			3.3	3.6	v
Low-level input voltage, V <sub>II</sub>	$V_{DD} = 3 V$ to 3.6 V			0.8	V
	$V_{DD} = 2.3 \text{ V to } 2.7 \text{ V}$			0.7	v
High lovel input veltage V	$V_{DD} = 3 V \text{ to } 3.6 V$	2			V
High-level input voltage, V <sub>IH</sub>	$V_{DD} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7			v
Input voltage, V <sub>I</sub>		0		$V_{DD}$	V
High lovel output ourrest	$V_{DD} = 3 V \text{ to } 3.6 V$			12	mA
High-level output current, I <sub>OH</sub>	$V_{DD} = 2.3 \text{ V to } 2.7 \text{ V}$			6	ША
	$V_{DD} = 3 V \text{ to } 3.6 V$			12	~ ^
Low-level output current, I <sub>OL</sub>	V <sub>DD</sub> = 2.3 V to 2.7 V			6	mA
Operating free-air temperature, $T_{\mu}$		-40		85	°C

(1) Unused inputs must be held high or low to prevent them from floating.

#### **ELECTRICAL CHARACTERISTICS**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP <sup>(1)</sup>	MAX	UNIT
VIK	Input voltage	$V_{DD} = 3 V,$	I <sub>I</sub> = -18 mA			-1.2	V
I <sub>I</sub>	Input current	$V_{I} = 0 V \text{ or } V_{DD}$				±5	μA
I <sub>DD</sub> <sup>(2)</sup>	Static device current	CLK = 0 V or V <sub>DD</sub> ,	$I_0 = 0 \text{ mA}$			80	μA
CI	Input capacitance	V <sub>DD</sub> = 2.3 V to 3.6 V,	$V_{I} = 0 V \text{ or } V_{DD}$		2.5		pF
Co	Output capacitance	V <sub>DD</sub> = 2.3 V to 3.6 V,	$V_{I} = 0 V \text{ or } V_{DD}$		2.8		pF

(1) All typical values are at respective nominal  $V_{DD}$ .

(2) For  $I_{CC}$  over frequency, see Figure 6.



# $V_{\text{DD}}$ = 3.3 V $\pm 0.3$ V

PARAMETER		TEST	TEST CONDITIONS		TYP <sup>(1)</sup>	MAX	UNIT
		V <sub>DD</sub> = min to max,	I <sub>OH</sub> = −100 μA	V <sub>DD</sub> – 0.2			
V <sub>OH</sub>	High-level output voltage	V - 2 V	I <sub>OH</sub> = -12 mA	2.1			V
		$V_{DD} = 3 V$	I <sub>OH</sub> =6 mA	2.4			
	V <sub>OL</sub> Low-level output voltage	V <sub>DD</sub> = min to max,	I <sub>OL</sub> = −100 μA			0.2	
V <sub>OL</sub>		V <sub>DD</sub> = 3 V	I <sub>OL</sub> = 12 mA			0.8	V
			I <sub>OL</sub> = 6 mA			0.55	
		V <sub>DD</sub> = 3 V,	V <sub>O</sub> = 1 V	-28			
I <sub>OH</sub>	High-level output current	V <sub>DD</sub> = 3.3 V,	V <sub>O</sub> = 1.65 V		-36		mA
		V <sub>DD</sub> = 3.6 V,	V <sub>O</sub> = 3.135 V			-14	
I <sub>OL</sub>		V <sub>DD</sub> = 3 V,	V <sub>O</sub> = 1.95 V	28			
	Low-level output current	V <sub>DD</sub> = 3.3 V,	V <sub>O</sub> = 1.65 V		36		mA
		V <sub>DD</sub> = 3.6 V,	V <sub>O</sub> = 0.4 V			14	

(1) All typical values are at respective nominal  $V_{\text{DD}}$ .

## $V_{\text{DD}} = 2.5 \text{ V} \pm 0.2 \text{ V}$

PARAMETER		TEST	TEST CONDITIONS		TYP <sup>(1)</sup>	MAX	UNIT
N	High lovel output veltage	V <sub>DD</sub> = min to max,	I <sub>OH</sub> = −100 μA	V <sub>DD</sub> - 0.2			V
V <sub>OH</sub>	High-level output voltage	V <sub>DD</sub> = 2.3 V	I <sub>OH</sub> = -6 mA	1.8			v
V	Low lovel output veltage	V <sub>DD</sub> = min to max,	I <sub>OL</sub> = 100 μA			0.2	V
VOL	V <sub>OL</sub> Low-level output voltage	V <sub>DD</sub> = 2.3 V	I <sub>OL</sub> = 6 mA			0.55	v
		V <sub>DD</sub> = 2.3 V,	$V_0 = 1 V$	-17			
I <sub>OH</sub>	High-level output current	V <sub>DD</sub> = 2.5 V,	V <sub>O</sub> = 1.25 V		-25		mA
		V <sub>DD</sub> = 2.7 V,	V <sub>O</sub> = 2.375 V			-10	
		V <sub>DD</sub> = 2.3 V,	V <sub>O</sub> = 1.2 V	17			
I <sub>OL</sub>	Low-level output current	V <sub>DD</sub> = 2.5 V,	V <sub>O</sub> = 1.25 V		25		mA
		V <sub>DD</sub> = 2.7 V,	$V_{O} = 0.3 V$			10	

(1) All typical values are at respective nominal  $V_{\text{DD}}.$ 

## TIMING REQUIREMENTS

over recommended ranges of supply voltage and operating free-air temperature

			MIN	NOM MA	xι	UNIT
f <sub>clk</sub> Clock frequency	Clock frequency	$V_{DD} = 3 V \text{ to } 3.6 V$	0	20	0	MHz
	$V_{DD} = 2.3 \text{ V to } 2.7 \text{ V}$	0	17	'0 <sup>'</sup>		



## SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

## $V_{DD}$ = 3.3 V ±0.3 V (SEE FIGURE 2)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	CLK to Yn	f = 0 MHz to 200 MHz For circuit load, see Figure 2.	1.3		2.8	ns
t <sub>sk(o)</sub>	Output skew (Ym to Yn) <sup>(1)</sup> (see Figure 4)				100	ps
t <sub>sk(p)</sub>	Pulse skew (see Figure 5)				250	ps
t <sub>sk(pp)</sub>	Part-to-part skew				500	ps
t <sub>r</sub>	Rise time (see Figure 3)	$V_{O} = 0.4 \text{ V} \text{ to } 2 \text{ V}$	0.7		2	V/ns
t <sub>f</sub>	Fall time (see Figure 3)	$V_0 = 2 V \text{ to } 0.4 V$	0.7		2	V/ns
t <sub>su(en)</sub>	Enable setup time, G_high before CLK $\downarrow$		0.1			ns
t <sub>su(dis)</sub>	Disable setup time, G_low before CLK $\downarrow$		0.1			ns
t <sub>h(en)</sub>	Enable hold time, G_high after CLK $\downarrow$		0.4			ns
t <sub>h(dis)</sub>	Disable hold time, G_low after CLK $\downarrow$		0.4			ns

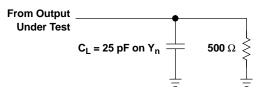
(1) The  $t_{sk(o)}$  specification is only valid for equal loading of all outputs.

## $V_{\text{DD}}$ = 2.5 V $\pm 0.2$ V (SEE FIGURE 2)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	CLK to Yn	f = 0 MHz to 170 MHz For circuit load, see Figure 2.	1.5		3.5	ns
t <sub>PHL</sub> t <sub>sk(o)</sub>	Output skew (Ym to Yn) <sup>(1)</sup> (see Figure 4)				170	ps
t <sub>sk(p)</sub>	Pulse skew (see Figure 5)				400	ps
t <sub>sk(pp)</sub>	Part-to-part skew				600	ps
t <sub>r</sub>	Rise time (see Figure 3)	$V_{O} = 0.4 \text{ V to } 1.7 \text{ V}$	0.5		1.4	V/ns
t <sub>f</sub>	Fall time (see Figure 3)	V <sub>O</sub> = 1.7 V to 0.4 V	0.5		1.4	V/ns
t <sub>su(en)</sub>	Enable setup time, G_high before CLK $\downarrow$		0.1			ns
t <sub>su(dis)</sub>	Disable setup time, G_low before CLK $\downarrow$		0.1			ns
t <sub>h(en)</sub>	Enable hold time, G_high after CLK $\downarrow$		0.4			ns
t <sub>h(dis)</sub>	Disable hold time, G_low after CLK $\downarrow$		0.4	•		ns

(1) The  $t_{sk(o)}$  specification is only valid for equal loading of all outputs.

#### PARAMETER MEASUREMENT INFORMATION



- A.  $C_L$  includes probe and jig capacitance.
- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  200 MHz, Z<sub>O</sub> = 50  $\Omega$ ,  $t_r$  < 1.2 ns,  $t_f$  < 1.2 ns.

#### Figure 2. Test Load Circuit



## PARAMETER MEASUREMENT INFORMATION (continued)

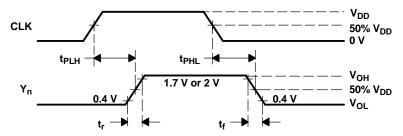


Figure 3. Voltage Waveforms Propagation Delay Times

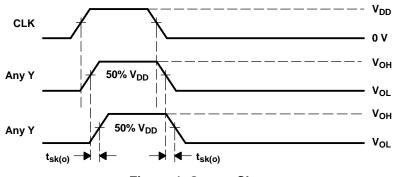
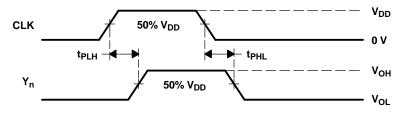


Figure 4. Output Skew



NOTE:  $t_{sk(p)} = |t_{PLH} - t_{PHL}|$ 

Figure 5. Pulse Skew



## PARAMETER MEASUREMENT INFORMATION (continued)

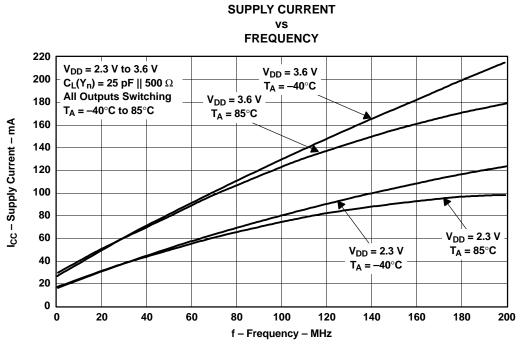
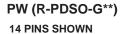


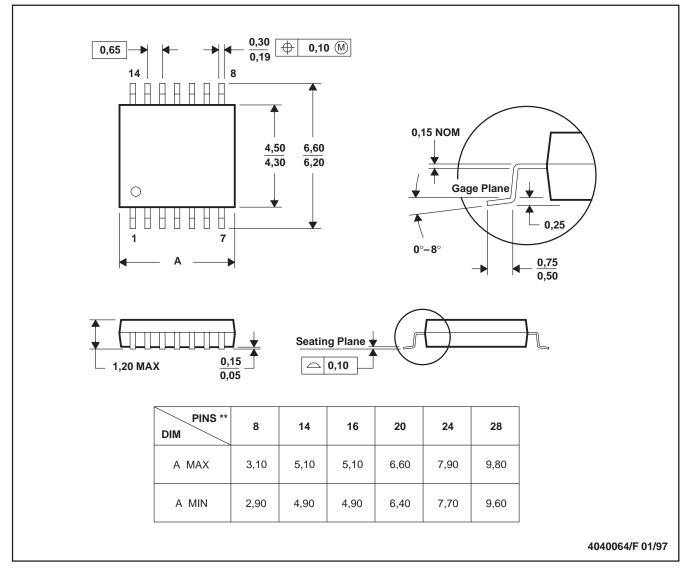
Figure 6.

# **MECHANICAL DATA**

MTSS001C - JANUARY 1995 - REVISED FEBRUARY 1999

#### PLASTIC SMALL-OUTLINE PACKAGE





NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



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